



O T P INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/607,840
		Filing Date	June 27, 2004
		First Named Inventor	Gregory R. Hanson
		Group Art Unit	2877
		Examiner Name	
Sheet	1	of	1
		Attorney Docket	UBAT1490-2

## **U.S. PATENT DOCUMENTS**

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		"	
Examiner Signature	<i>PATRICK CONNOLLY</i>		Date Considered <i>11.29.2005</i>

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